

N/P DIODE

SEMICONDUCTOR REVERSE RECOVERY TIME TESTER

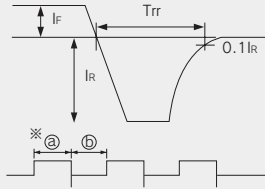
半導体逆回復時間測定器

TRR-N05M

±500mA



Measurement Waveform



2-MULTIPLEXER Function

Measurement is repeated 10 times and the average is considered as T_{rr} .

| ※ | TRR-E2C | TRDI-PN100 | TRR-PN100A | TRRZ-N05M |
|---|---------|-------------|-------------|-------------|
| Ⓐ | T_w | 100 μ s | 100 μ s | 100 μ s |
| Ⓑ | | 100 μ s | 100 μ s | 1ms |

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TRR-PN100A

±100mA
FIX



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TRDI-PN100

±100mA
FIX



| MODEL | TRRZ-N05M | TRR-PN100A | TRDI-PN100 |
|--------------------------------|---|---|---|
| MEASUREMENT RANGE | | | |
| IF | 100mA~499mA | +100mA(FIX) | +100mA(FIX) |
| IR | -100mA~-499mA | -100mA(FIX) | -100mA(FIX) |
| T_w | 100 μ s | 100 μ s | — |
| MEASUREMENT RANGE(T_{rr}) | 0.000 μ s~9.999 μ s | 30ns~999ns(± 1 DIGIT) | 10ns~9.99 μ s(2 RANGES) |
| DETECTION TIMING | 10%~40% | 10%, 25% | 10% FIX |
| BINNING AND INTERFACE | | | |
| PRE OPEN/SHORT | IF ON : $V_f > 2V$...OPEN IF ON : $V_f < 0.2V$...SHORT | IF ON : $V_f > 2V$...OPEN IF ON : $V_f < 0.2V$...SHORT | IF ON : $V_f > 2V$...OPEN IF ON : $V_f < 0.1V$...SHORT |
| BIN INDICATION | PASS, HIGH, OPEN, SHORT | PASS, LOW, HIGH, OPEN/SHORT | OPEN, SHORT, HIGH, LOW, PASS |
| EXTERNAL I/F | Handler-I/F STANDARD | Handler-I/F STANDARD | Handler-I/F STANDARD |
| EXT CONTROL I/F | RS-232C I/F | IEEE-488 I/F STANDARD(GP-IB) | IEEE-488 I/F STANDARD(GP-IB) |
| DIMENSIONS & WEIGHT | | | |
| MAIN UNIT | 430(W)×700(D)×245(H)···35kg | 300(W)×200(D)×75(H)···2kg | 270(W)×450(D)×235(H)···20kg |
| HEAD BOX | 105(W)×290(D)×210(H)···3kg | — | 75(W)×150(D)×150(H)···1kg |